

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10520787	MIYOSHI ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Miah, Liton	2617

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	329	9/25/2007	Liton Miah
370	331	9/25/2007	Liton Miah
370	235	9/25/2007	Liton Miah
714	707	9/25/2007	Liton Miah
714	708	9/25/2007	Liton Miah
714	704	9/25/2007	Liton Miah
Search	Updated	3/18/2008	Liton Miah
Search	Updated	6/19/2008	Liton Miah
Search	Updated	12/15/2008	Liton Miah

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST (US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB)	9/25/2007	Liton Miah
Consulted with Spe (Rafael Gutierrez-Perez)	9/25/2007	Liton Miah
Inventorship Search	9/25/2007	Liton Miah
Search Updated	3/18/2008	Liton Miah
Search Updated	6/19/2008	Liton Miah
Search Updated	12/15/2008	Liton Miah
Consulted with Spe (Rafael Gutierrez-Perez)	3/11/2009	Liton Miah
Search Updated	3/16/2009	Liton Miah
Search Updated	10/22/2009	Liton Miah
search updated	4/23/2010	Liton Miah
Consulted with Spe (Rafael Gutierrez-Perez)	9/23/2010	Liton Miah
search updated	9/24/2010	Liton Miah

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>